



Technical Information Service Report

TIS Report: 80235489
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Issued by: Xueji Dong

SUBJECT: Custom test to cloud platform according to OpenADR2.0b. Model Elecq Charger, Type VEN

APPLICABLE REQUIREMENTS:

1. OpenADR 2.0 Profile Specification B Profile V1.1
2. OpenADR 2.0b Certification Test Specification V1.1.2

ASSESSMENT:

Please supply a copy of this information when filing an application for CSA Certification related to the SUBJECT, as it may aid the investigation.

Test Summary

OpenADR 2.0b is an application layer message exchange specification used for two-way communication of Demand Response (DR), price, and Distributed Energy Resource (DER) signals between the electricity service provider and its customers. The scope of the test cases will focus on validating the successful exchange of messages between VTNs and VENs, validating that any exceptions are handled gracefully and without service interruptions and that security mechanisms are properly implemented. Validating the functional behavior of the DUT in response to payload content is out of scope for the certification tests.

THIS REPORT DOES NOT AUTHORIZE THE USE OF THE CSA MARK ON THE SUBJECT PRODUCTS.

The completion of this form does not imply certification or approval of the "SUBJECT" product nor any features or components thereof.

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Device(s) Identification

Device under test Information:

Product Name	Elecq Charger
Product Model	N/A
Product Type	VEN
Firmware Version	V1.0
OpenADR Profile	2.0b
Security	RSA
Transport Protocol	Simple HTTP
Pull/Push Mode	Pull Mode

Test Tool information:

Tool Company	QualityLogic
Tool Name	OpenADR2.0 A&B Test Harness
Tool Version	V1.1.7

2.Test Configuration

Test Setup



Test Procedures

The device under test is software implementation of OpenADR protocol installed on Cloud. The test had been completed on December 5, 2024.

3.Test Result

Summary Convention

The following “Result” convention is used in this summary.

Result Items	Description
PASS	means the performed test was verified and that the tested device is conformant to the test specification.
SKIP	means the PICS test case guidelines allowed test case to be skipped
N/A	means the test cases are optional or not applicable to the tested device

Summary of Test Results

1. EiRegisterParty Service Test

No.	Test Case Name	Test Result
1	N1_0010_TH_VTN1	PASS
2	N1_0015_TH_VTN1	PASS
3	N1_0020_TH_VTN1	PASS
4	N1_0025_TH_VTN1	PASS
5	N1_0030_TH_VTN1	PASS
6	N1_0040_TH_VTN1	PASS
7	N1_0050_TH_VTN1	PASS
8	N1_0060_TH_VTN1	PASS
9	N1_0065_TH_VTN1	PASS
10	N1_0070_TH_VTN1	PASS
11	N1_0080_TH_VTN1	N/A

2. General Test

No.	Test Case Name	Test Result
1	G1_4005_TH_VTN_1	PASS
2	G1_4007_TH_VTN_1	PASS
3	G1_4010_TH_VTN_1	N/A
4	G1_4011_TH_VTN_1	N/A
5	G1_4012_TH_VTN_1	PASS
6	G1_4015_TH_VTN_1	PASS
7	G1_4030_TH_VTN_1	PASS

3. EiOpt Service Test

No.	Test Case Name	Test Result
1	P1_2010_TH_VTN_1	PASS
2	P1_2015_TH_VTN_1	PASS
3	P1_2020_TH_VTN_1	PASS
4	P1_2030_TH_VTN_1	PASS
5	P1_2040_TH_VTN_1	PASS
6	P1_2050_TH_VTN_1	PASS

4. EiReport Service Test

No.	Test Case Name	Test Result
1	R1_3010_TH_VTN_1	PASS
2	R1_3020_TH_VTN_1	PASS
3	R1_3025_TH_VTN_1	PASS
4	R1_3027_TH_VTN_1	PASS
5	R1_3030_TH_VTN_1	PASS
6	R1_3040_TH_VTN_1	PASS
7	R1_3045_TH_VTN_1	PASS
8	R1_3050_TH_VTN_1	PASS
9	R1_3060_TH_VTN_1	N/A

No.	Test Case Name	Test Result
10	R1_3070_TH_VTN_1	SKIP
11	R1_3080_TH_VTN_1	SKIP
12	R1_3090_TH_VTN_1	SKIP
13	R1_3100_TH_VTN_1	SKIP
14	R1_3120_TH_VTN_1	SKIP
15	R1_3130_TH_VTN_1	SKIP
16	R1_3150_TH_VTN_1	PASS
17	R1_3160_TH_VTN_1	PASS
18	R1_3170_TH_VTN_1	PASS
19	R1_3180_TH_VTN_1	PASS
20	R1_3190_TH_VTN_1	PASS

5. EiEvent Service Test

No.	Test Case Name	Test Result
1	E1_1010_TH_VTN_1	PASS
2	E1_1020_TH_VTN_1	PASS
3	E1_1025_TH_VTN_1	PASS
4	E1_1027_TH_VTN_1	PASS
5	E1_1030_TH_VTN_1	PASS
6	E1_1040_TH_VTN_1	PASS
7	E1_1050_TH_VTN_1	PASS
8	E1_1055_TH_VTN_1	PASS
9	E1_1060_TH_VTN_1	PASS
10	E1_1065_TH_VTN_1	PASS
11	E1_1070_TH_VTN_1	PASS
12	E1_1080_TH_VTN_1	PASS
13	E1_1090_TH_VTN_1	PASS

6. EiEvent Ported A Profile Test

No.	Test Case Name	Test Result
1	A_E1_0020_TH_VTN_1	PASS
2	A_E1_0040_TH_VTN_1	PASS
3	A_E1_0060_TH_VTN_1	PASS
4	A_E1_0070_TH_VTN_1	PASS
5	A_E1_0082_TH_VTN_1	PASS
6	A_E1_0086_TH_VTN_1	PASS
7	A_E1_0090_TH_VTN_1	PASS
8	A_E1_0092_TH_VTN_1	PASS
9	A_E1_0094_TH_VTN_1	PASS
10	A_E1_0096_TH_VTN_1	PASS
11	A_E1_0098_TH_VTN_1	PASS
12	A_E1_0100_TH_VTN_1	PASS
13	A_E1_0102_TH_VTN_1	PASS
14	A_E1_0104_TH_VTN_1	PASS
15	A_E1_0110_TH_VTN_1	PASS
16	A_E1_0130_TH_VTN_1	PASS
17	A_E1_0180_TH_VTN_1	PASS

No.	Test Case Name	Test Result
18	A_E1_0190_TH_VTN_1	PASS
19	A_E1_0200_TH_VTN_1	PASS
20	A_E1_0210_TH_VTN_1	PASS
21	A_E1_0220_TH_VTN_1	PASS
22	A_E1_0230_TH_VTN_1	PASS
23	A_E1_0240_TH_VTN_1	PASS
24	A_E1_0250_TH_VTN_1	PASS
25	A_E1_0260_TH_VTN_1	PASS
26	A_E1_0262_TH_VTN_1	PASS
27	A_E1_0267_TH_VTN_1	PASS
28	A_E1_0268_TH_VTN_1	PASS
29	A_E1_0270_TH_VTN_1	PASS
30	A_E1_0280_TH_VTN_1	PASS
31	A_E1_0285_TH_VTN_1	PASS
32	A_E1_0300_TH_VTN_1	PASS
33	A_E1_0310_TH_VTN_1	PASS
34	A_E1_0340_TH_VTN_1	PASS
35	A_E1_0345_TH_VTN_1	PASS
36	A_E1_0360_TH_VTN_1	PASS
37	A_E1_0370_TH_VTN_1	PASS
38	A_E1_0390_TH_VTN_1	PASS
39	A_E1_0392_TH_VTN_1	PASS

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